

S/N Unknown

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Klaus F. Schuegraf et.al. Examiner: Unknown
Serial No.: Unknown Group Art Unit: Unknown
Filed: Herewith Docket: 303.278US2
Title: SELECTIVE SPACER TO PREVENT METAL OXIDE FORMATION DURING
POLYCIDE REOXIDATION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement. However, if an Office Action on the merits has been mailed, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Information Disclosure Statement considered.

Pursuant to 37 C.F.R. §1.98(d), copies of the listed documents are not provided as these references were previously cited by or submitted to the U.S. Patent Office in connection with Applicants' prior U.S. application, Serial No. 08/902809, filed on July 30, 1997, which is relied upon for an earlier filing date under 35 U.S.C. §120.

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COMMUNICATION CONCERNING RELATED APPLICATION(S)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
08/902808 5925918	July 30, 1997	303.192US1	GATE STACK WITH IMPROVED SIDEWALL INTEGRITY
09/097353 5998290	June 15, 1998	303.192US2	METHOD TO PROTECT GATE STACK MATERIAL DURING SOURCE/DRAIN REOXIDATION
09/323178 6075274	May 28, 1999	303.192US3	SEMICONDUCTOR DEVICES HAVING GATE STACK WITH IMPROVED SIDEWALL INTEGRITY

Respectfully submitted,

KLAUS F. SCHUEGRAF ET AL.

By Applicants' Representatives,

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Date 27 February 2004 By Robert E. Mates
Reg. No. 35,271 

"Express Mail" mailing label number: EV370240125US

Date of Deposit: February 27, 2004

This paper or fee is being deposited on the date indicated above with the United States Postal Service pursuant to 37 CFR 1.10, and is addressed to The Commissioner for Patents, Mail Stop Patent Application, P.O. Box 1450, Alexandria, VA 22313-1450.

INFORMATION DISCLOSURE STATEMENT

Serial No :Unknown

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Title: SELECTIVE SPACER TO PREVENT METAL OXIDE FORMATION DURING POLYCIDE REOXIDATION

Page 2

Dkt: 303.278US2

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

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Substitute for form 1449A/PTO		Complete if Known				
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Application Number	Unknown			
		Filing Date	Even Date Herewith			
		First Named Inventor	Schuegraf, Klaus			
		Group Art Unit	Unknown			
		Examiner Name	Unknown			
Sheet 1 of 2		Attorney Docket No: 303.278US2				

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Complete if Known				
		Application Number		Unknown		
		Filing Date		Even Date Herewith		
		First Named Inventor		Schuegraf, Klaus		
		Group Art Unit		Unknown		
		Examiner Name		Unknown		
Sheet 2 of 2		Attorney Docket No: 303.278US2				

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